

MJLM148-X REV 0C1

Original Creation Date: 08/08/95

Last Update Date: 04/12/99

Last Major Revision Date: 08/08/95

QUAD OPERATIONAL, MEDIUM POWER, INTERNALLY COMPENSATED AMPLIFIER

General Description

The LM148 series is a true quad LM741. It consists of four independent, high gain, internally compensated, low power operational amplifiers which have been designed to provide functional characteristics identical to those of the familiar LM741 operational amplifier. In addition the total supply current for all four amplifiers is comparable to the supply current of a LM741 type op amp. Other features include input offset currents and input bias current which are much less than those of a standard LM741. Also, excellent isolation between amplifiers has been achieved by independently biasing each amplifier and using layout techniques which minimize thermal coupling.

The LM148 can be used anywhere multiple LM741 or LM1558 type amplifiers are being used and in applications where amplifier matching or high packing density is required.

Industry Part Number

LM148

Prime Die

LM148

NS Part Numbers

JL148BCA

JL148BDA

JL148BZA

JL148SCA

JL148SDA

Controlling Document

38510/11001, AMEND. 3 REV B

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

Features

- 741 op amp operating characteristics
- Low supply current drain 0.6mA/Amplifier
- Class AB output stage-no crossover distortion
- Pin compatible with the LM124
- Low input offset voltage 1mV
- Low input offset current 4nA
- Low input bias current 30nA
- Gain bandwidth product (Unity Gain) 1.0Mhz
- High degree of isolation between amplifiers 120dB
- Overload protection for input and outputs

(Absolute Maximum Ratings)

(Note 1)

Supply Voltage	± 22V
Input Voltage Range	± 20V
Input Current Range	-0.1mA to 10mA
Differential Input Voltage Range (Note 2)	± 30V
Output Short Circuit Duration (Note 3)	Continuous
Power Dissipation (Note 4)	
(Pd at 25 C)	
CERDIP	400mW
CERPACK	350mW
Maximum Junction Temperature (TjMAX)	175 C
Operating Temperature Range	-55 C ≤ TA ≤ +125 C
Storage Temperature Range	-65 C to +150 C
Lead Temperature (Soldering, 10 seconds)	300 C
Thermal Resistance	
ThetaJA	
CERDIP	(Still Air) 103 C/W
	(500LF/Min Air Flow) 52 C/W
CERPACK	(Still Air) 140 C/W
	(500LF/Min Air Flow) 100 C/W
CERAMIC SOIC	(Still Air) 176 C/W
	(500LF/Min Air Flow) 116 C/W
ThetaJC	
CERDIP	19 C/W
CERPACK	25 C/W
CERAMIC SOIC	25 C/W
Package Weight (Typcial)	
CERDIP	TBD
CERPACK	465mg
CERAMIC SOIC	415mg
ESD Tolerance (Note 5)	500V

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: The differential input voltage range shall not exceed the supply voltage range.

Note 3: Any of the amplifier outputs can be shorted to ground indefinitely; however, more than one should not be simultaneously shorted as the maximum junction temperature will be exceeded.

Note 4: The maximum power dissipation for these devices must be derated at elevated temperatures and is dictated by TjMAX, ThetaJA, and the ambient temperature, TA. The maximum available power dissipation at any temperature is Pd=(TjMAX - TA)/ThetaJA or the 25 C PdMAX, whichever is less.

Note 5: Human body model, 1.5K Ohms in series with 100pF.

Electrical Characteristics

DC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier.

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Vio	Input Offset Voltage	$+V_{CC} = 35V$, $-V_{CC} = -5V$, $V_{CM} = -15V$			-5	5	mV	1
					-6	6	mV	2, 3
		$+V_{CC} = 5V$, $-V_{CC} = -35V$, $V_{CM} = +15V$			-5	5	mV	1
					-6	6	mV	2, 3
					-5	5	mV	1
					-6	6	mV	2, 3
		$+V_{CC} = 5V$, $-V_{CC} = -5V$			-5	5	mV	1
					-6	6	mV	2, 3
Delta Vio/Delta T	Input Offset Voltage Temperature Stability	$25\text{ }^{\circ}\text{C} \leq T_A \leq 125\text{ }^{\circ}\text{C}$	1		-25	25	$\mu\text{V}/^{\circ}\text{C}$	2
		$-55\text{ }^{\circ}\text{C} \leq T_A \leq 25\text{ }^{\circ}\text{C}$	1		-25	25	$\mu\text{V}/^{\circ}\text{C}$	3
Iio	Input Offset Current	$+V_{CC} = 35V$, $-V_{CC} = -5V$, $V_{CM} = -15V$			-25	25	nA	1, 2
					-75	75	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -35V$, $V_{CM} = +15V$			-25	25	nA	1, 2
					-75	75	nA	3
					-25	25	nA	1, 2
					-75	75	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -5V$			-25	25	nA	1, 2
					-75	75	nA	3
Delta Iio/Delta T	Input Offset Current Temperature Stability	$25\text{ }^{\circ}\text{C} \leq T_A \leq 125\text{ }^{\circ}\text{C}$	1		-200	200	$\text{pA}/^{\circ}\text{C}$	2
		$-55\text{ }^{\circ}\text{C} \leq T_A \leq 25\text{ }^{\circ}\text{C}$	1		-400	400	$\text{pA}/^{\circ}\text{C}$	3
+Iib	Input Bias Current	$+V_{CC} = 35V$, $-V_{CC} = -5V$, $V_{CM} = -15V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -35V$, $V_{CM} = +15V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3
					-0.1	100	nA	1, 2
					-0.1	325	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -5V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3

Electrical Characteristics

DC PARAMETERS(Continued)

(The following conditions apply to all the following parameters, unless otherwise specified.)

DC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier.

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
-I _{ib}	Input Bias Current	$+V_{CC} = 35V$, $-V_{CC} = -5V$, $V_{CM} = -15V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -35V$, $V_{CM} = +15V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3
					-0.1	100	nA	1, 2
					-0.1	325	nA	3
		$+V_{CC} = 5V$, $-V_{CC} = -5V$			-0.1	100	nA	1, 2
					-0.1	325	nA	3
+PSRR	Power Supply Rejection Ratio	$-V_{CC} = -20V$, $+V_{CC} = 20$ to $10V$	2		-100	100	uV/V	1, 2, 3
-PSRR	Power Supply Rejection Ratio	$+V_{CC} = 20V$, $-V_{CC} = -20$ to $-10V$	2		-100	100	uV/V	1, 2, 3
CMR	Common Mode Rejection	$\pm 5V \leq \pm V_{CC} \leq \pm 35V$, $V_{CM} = \pm 15V$			76		dB	1, 2, 3

Electrical Characteristics

DC/AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)

DC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier.

AC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier.

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Ios+	Short Circuit Current	$+V_{CC} = 15V$, $-V_{CC} = -15V$, $V_{CM} = -10V$			-55		mA	1, 2
					-75		mA	3
Ios-	Short Circuit Current	$+V_{CC} = 15V$, $-V_{CC} = -15V$, $V_{CM} = 10V$				55	mA	1, 2
						75	mA	3
Icc	Power Supply Current	$+V_{CC} = 15V$, $-V_{CC} = -15V$				3.6	mA	1, 2
						4.5	mA	3
+Vop	Output Voltage Swing	$R_L = 10K\ \text{ohms}$			16		V	4, 5, 6
		$R_L = 2K\ \text{ohms}$			15		V	4, 5, 6
-Vop	Output Voltage Swing	$R_L = 10K\ \text{ohms}$				-16	V	4, 5, 6
		$R_L = 2K\ \text{ohms}$				-15	V	4, 5, 6
Avs-	Open Loop Voltage Gain	$V_{out} = -15V$, $R_L = 10K\ \text{Ohms}$			50		V/mV	4
					25		V/mV	5, 6
		$V_{out} = -15V$, $R_L = 2K\ \text{Ohms}$			50		V/mV	4
					25		V/mV	5, 6
Avs+	Open Loop Voltage Gain	$V_{out} = +15V$, $R_L = 10K\ \text{Ohms}$			50		V/mV	4
					25		V/mV	5, 6
		$V_{out} = +15V$, $R_L = 2K\ \text{Ohms}$			50		V/mV	4
					25		V/mV	5, 6
Avs	Open Loop Voltage Gain	$\pm V_{CC} = \pm 5V$, $V_{out} = \pm 2V$, $R_L = 10K\ \text{Ohms}$			10		V/mV	4, 5, 6
		$\pm V_{CC} = \pm 5V$, $V_{out} = \pm 2V$, $R_L = 2K\ \text{Ohms}$			10		V/mV	4, 5, 6
TR(tr)	Transient Response Time	$V_{in} = 50mV$, $A_v = 1$				1	μS	7, 8A, 8B
TR(os)	Transient Response Time	$V_{in} = 50mV$, $A_v = 1$				25	%	7, 8A, 8B
Sr+	Slew Rate	$V_{in} = -5V\ \text{to}\ +5V$, $A_v = 1$			.2		V/ μS	7, 8A, 8B
Sr-	Slew Rate	$V_{in} = +5V\ \text{to}\ -5V$, $A_v = 1$			.2		V/ μS	7, 8A, 8B

Electrical Characteristics

AC PARAMETERS

(The following conditions apply to all the following parameters, unless otherwise specified.)

AC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier.

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
NI(BB)	Noise (Broadband)	Bw = 10Hz to 5KHz				15	μV_{rms}	7
NI(PC)	Noise (Popcorn)	Rs = 20K Ohms				40	μV_{pk}	7
Cs	Channel Separation	Vin = $\pm 10V$, A to B, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, A to C, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, A to D, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, B to A, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, B to C, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, B to D, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, C to A, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, C to B, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, C to D, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, D to A, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, D to B, Rl = 2K Ohms			80		dB	7
		Vin = $\pm 10V$, D to C, Rl = 2K Ohms			80		dB	7

DC PARAMETERS: DRIFT VALUES

(The following conditions apply to all the following parameters, unless otherwise specified.)

DC: $\pm V_{CC} = \pm 20V$, $V_{CM} = 0V$, measure each amplifier. "Delta calculations performed on JAN S and QMLV devices at group B, subgroup 5 only".

Vio	Input Offset Voltage				-1	1	mV	1
+Iib	Input Bias Current				-15	15	nA	1
-Iib	Input Bias Current				-15	15	nA	1

Note 1: Calculated Parameter.

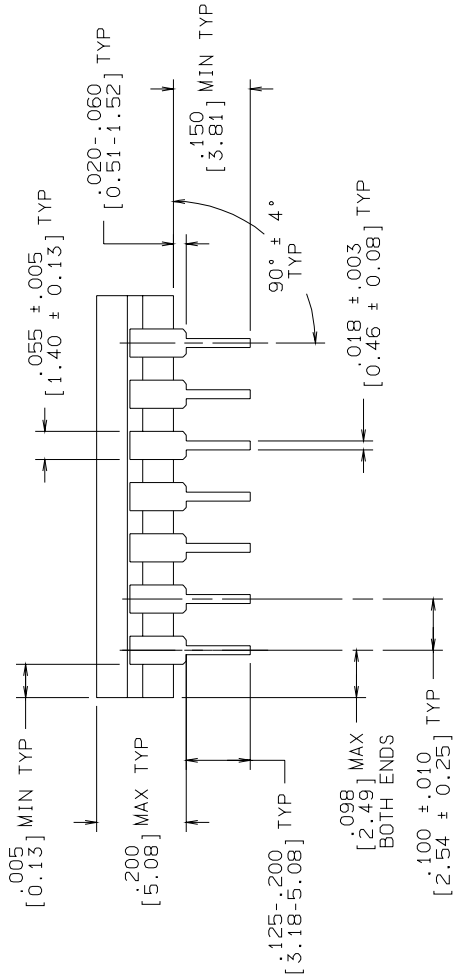
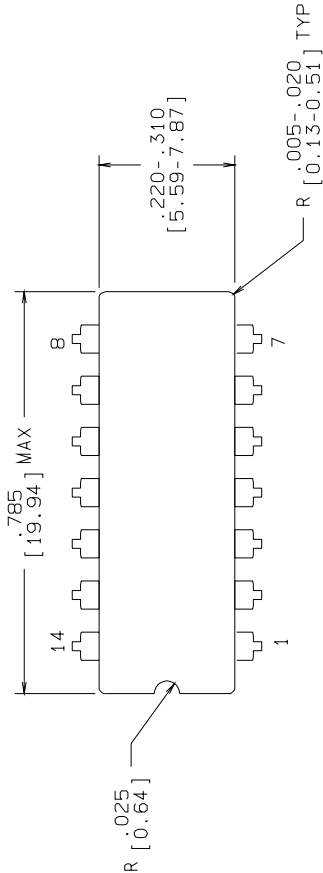
Note 2: Datalogs as μV .

Graphics and Diagrams

GRAPHICS#	DESCRIPTION
05324HRA2	CERDIP (J), 14LD (B/I CKT)
06203HRA2	CERPACK (W), 14LD (B/I CKT)
J14ARH	CERDIP (J), 14 LEAD (P/P DWG)
P000229A	CERDIP (J), 14 LEAD (PINOUT)
P000367A	CERPACK (W), 14 LEAD (PINOUT)
P000370A	CERAMIC SOIC (WG), 14 LEAD (PINOUT)
W14BRN	CERPACK (W), 14 LEAD (P/P DWG)
WG14ARB	CERAMIC SOIC (WG), 14LD (P/P DWG)

See attached graphics following this page.

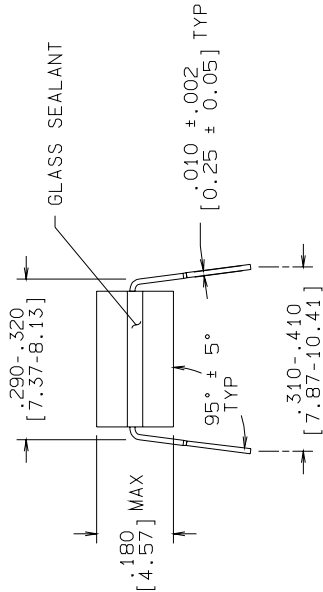
R E V I S I O N S				
LTR	DESCRIPTION	E.C.N.	DATE	BY/APP'D
H	REVISE PER CURRENT STD; REDRAW	10001	09/15/93	TL/



CONTROLLING DIMENSION: INCH

NOTES: UNLESS OTHERWISE SPECIFIED

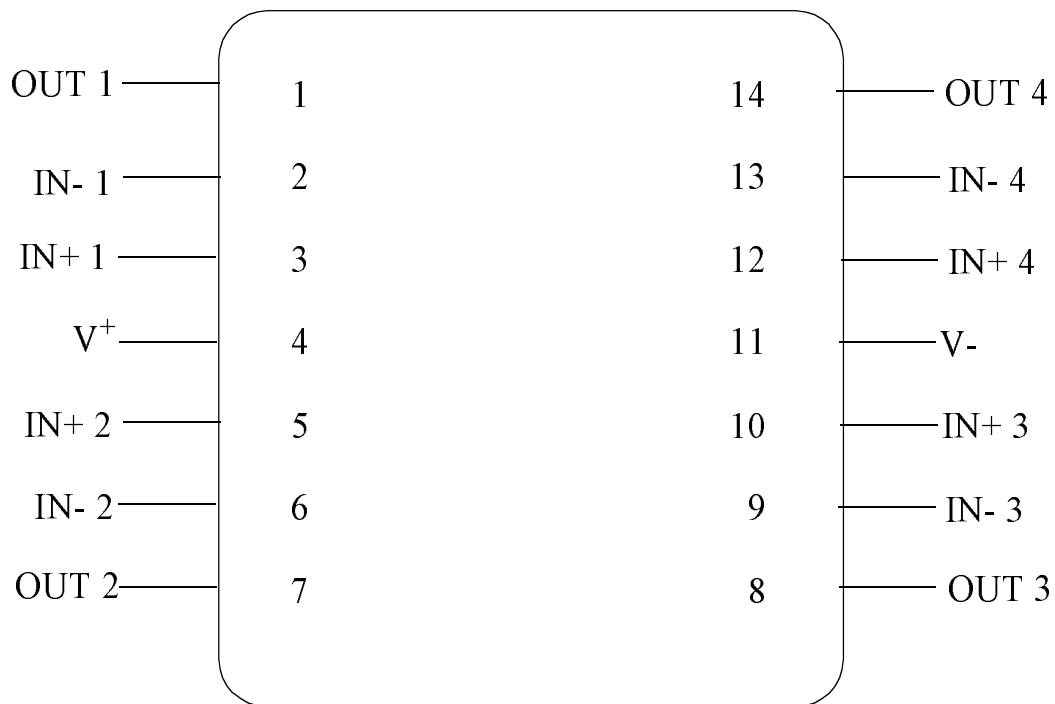
1. LEAD FINISH TO BE 200 MICROMETERS / 5.08 MICROMETERS MINIMUM SOLDER MEASURED AT THE CREST OF THE MAJOR FLATS.
2. JEDEC REGISTRATION MO-036, VARIATION AB, DATED 04/1981.



MIL/AERO MIL-M-38510
CONFIGURATION CONTROL CONFIGURATION CONTROL

APPROVALS	DATE	NATIONAL SEMICONDUCTOR CORPORATION		
DRAWN LEQUANG	09/15/93	2900 Semiconductor Drive, Santa Clara, CA 95052-8090		
DFTG. CHK.				
ENGR. CHK.				
APPROVAL				
PROJECTION		SCALE	SIZE	DRAWING NUMBER
		N/A	B	MKT-J14A
		DO NOT SCALE	DRAWING	SHEET 1 OF 1
				REV H

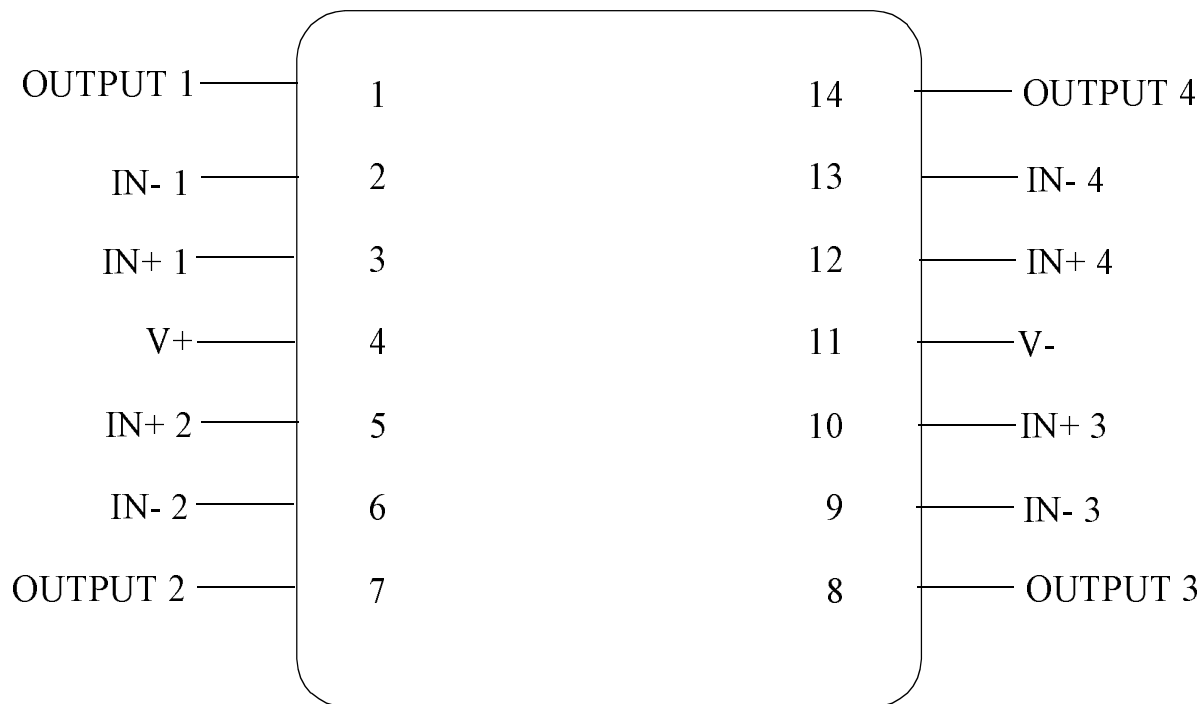
CERDIP (J) ,
14 LEAD,



LM148J
14 - LEAD DIP
CONNECTION DIAGRAM
TOP VIEW
P000229A



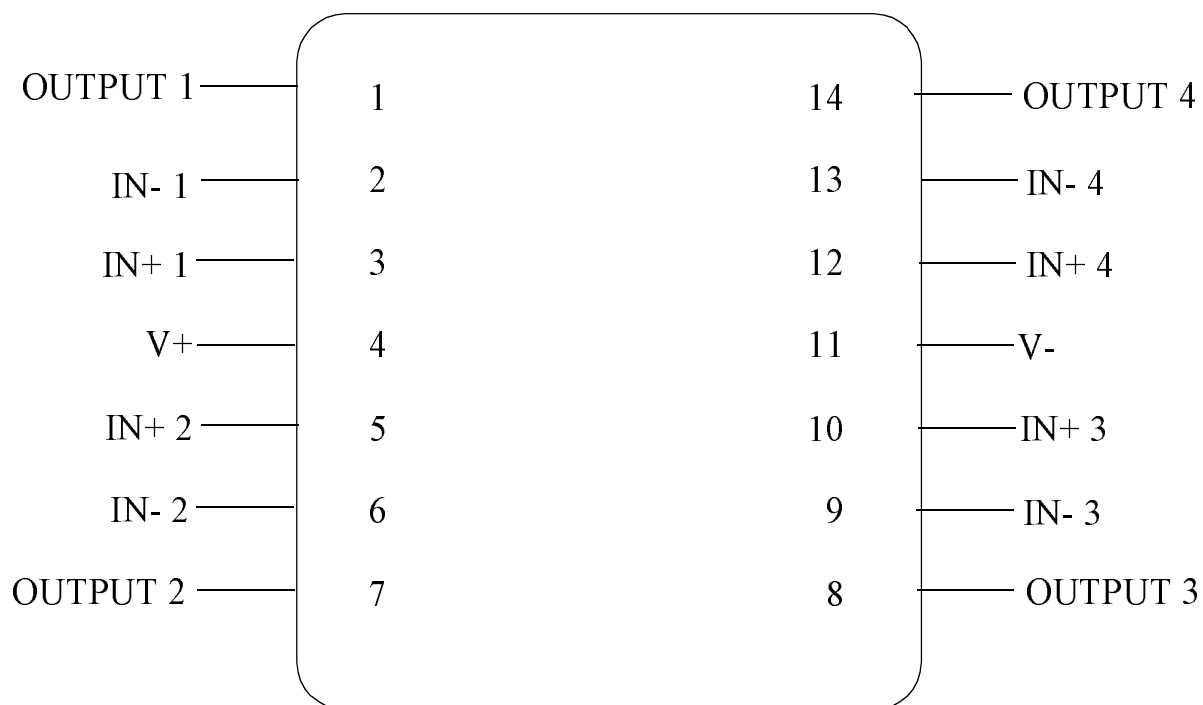
National Semiconductor™
MIL/AEROSPACE OPERATIONS
2900 SEMICONDUCTOR DRIVE
SANTA CLARA, CA 95050



LM148W
 14 - LEAD CERPACK
 CONNECTION DIAGRAM
 TOP VIEW
 P000367A



National Semiconductor™
 MIL/AEROSPACE OPERATIONS
 2900 SEMICONDUCTOR DRIVE
 SANTA CLARA, CA 95050



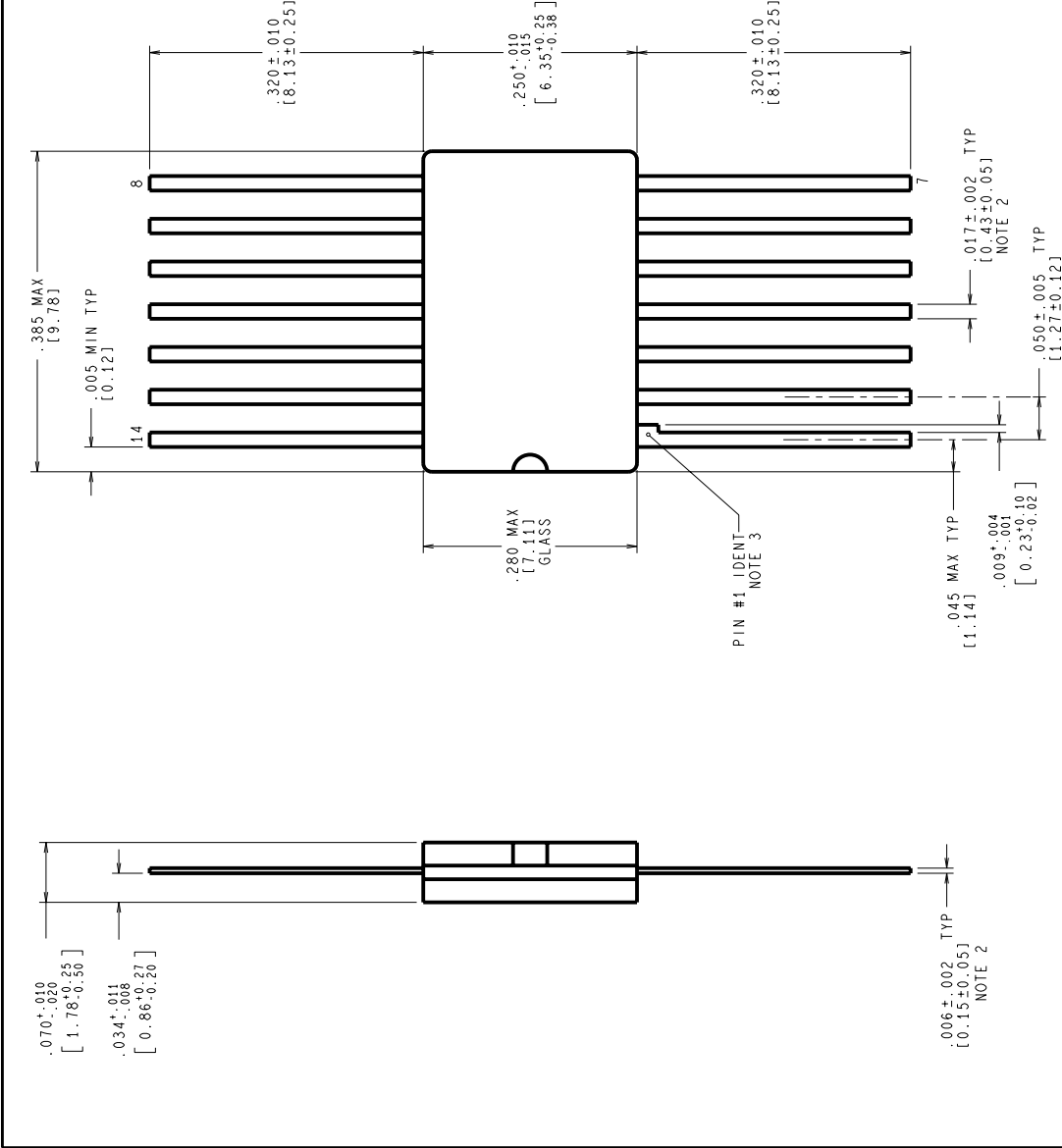
LM148WG
14 - LEAD CERAMIC SOIC
CONNECTION DIAGRAM
TOP VIEW
P000370A



National Semiconductor™

MIL/AEROSPACE OPERATIONS
 2900 SEMICONDUCTOR DRIVE
 SANTA CLARA, CA 95050

REVISIONS			
LTR	DESCRIPTION	E.C.N.	DATE
L	REVISE AND REDRAW PER NEW STANDARD.	10513	07/26/94
M	.017±.002 WAS .017±.020.	10655	10/21/94
N	L/F THRS. .004±.002 WAS .005±.001; UPDATE NOTES 1 & 2; REMOVE NOTE 4; UPDATE MILAERO STAMP; DUAL DIM'S WERE INCHES ONLY.	11005	06/08/95
			MS/



MIL-I-38535
CONFIGURATION CONTROL

CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

NOTES: UNLESS OTHERWISE SPECIFIED.

1. LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-I-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/ 5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE.

2. MAXIMUM LIMIT MAY BE INCREASED BY .003 INCHES/ 0.08 MILLIMETERS AFTER LEAD FINISH APPLIED.

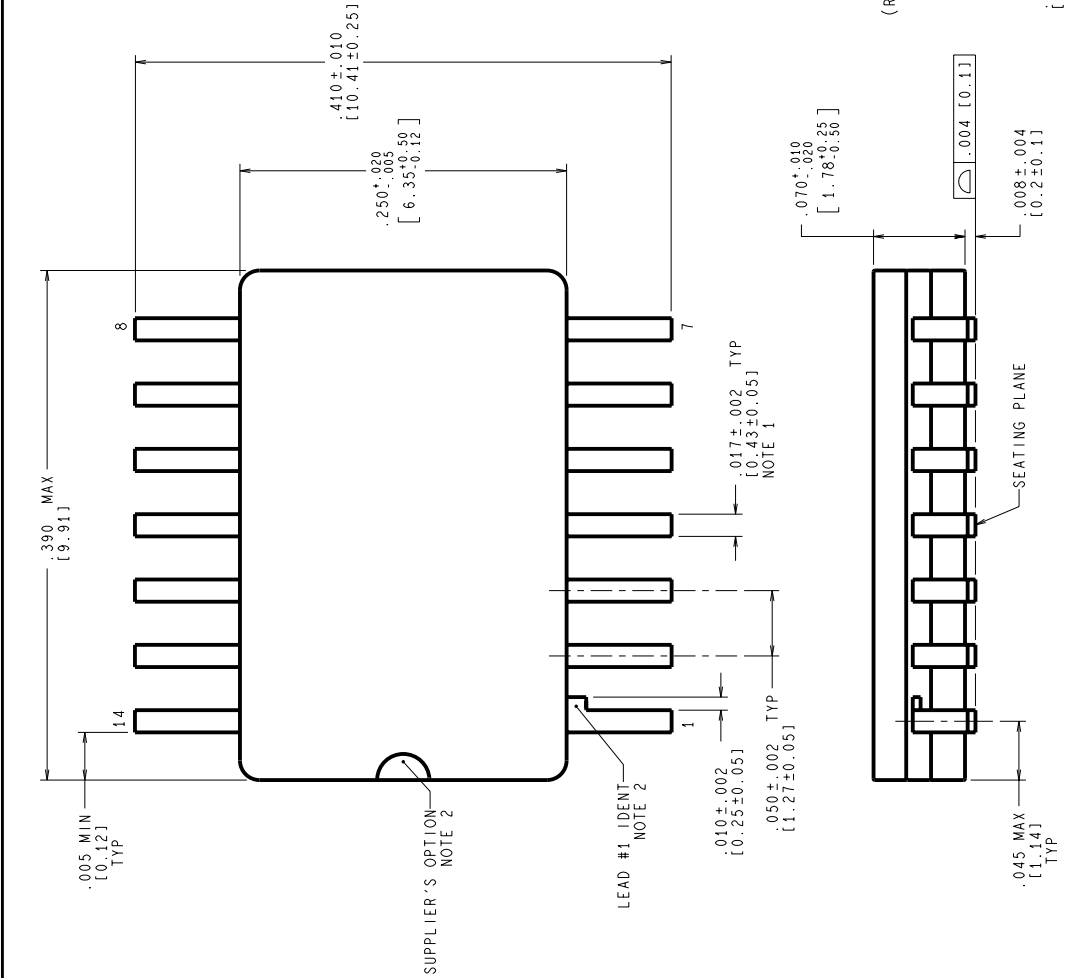
3. LEAD 1 IDENTIFICATION SHALL BE:
a) A NOTCH OR OTHER MARK WITHIN THIS AREA
b) A TAB ON LEAD 1, EITHER SIDE

APPROVALS		DATE				
DESIGN	<i>D. L. Grady</i>	07/26/94				
DATE						
DATE						
DATE						
PROJECTION			SCALE	SIZE	DRAWING NUMBER	REV
			N/A	C	MKT-W14B	N
			DO NOT SCALE DRAWING			
			SHEET 1 of 1			

National Semiconductor
2500 Semiconductor Dr., Santa Clara, CA 95052-8000

CERPACK, 14 LEAD

REVISIONS			
LTR	DESCRIPTION	E.C.N.	DATE
A	RELEASE TO DOCUMENT CONTROL	11375	02/29/96
B	LD PITCH TOL WAS $\pm .005$; CHANGE LD RADIUS TO REF DIM; REMOVE THE OTHER R .006 $\pm .002$	11442	04/15/96
			MS/



NOTES: UNLESS OTHERWISE SPECIFIED

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-PRF-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE. MAXIMUM LIMIT MAY BE INCREASED BY .003 IN/ 0.08mm AFTER LEAD FINISH APPLIED.
- LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
- NO JEDEC REGISTRATION AS OF FEBRUARY 1996.

CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

MIL-PRF-38535 CONFIGURATION CONTROL

APPROVALS		DATE	DRAWING NUMBER				REV
DESIGN	DATE	02/29/96	SCALE	SIZE	C	MKT-WG14A	B
DRY	MARIA SUCHY						
DATE	CHK						
DATE	CHK						
PROJECTION							
DO NOT SCALE DRAWING							
SHEET 1 of 1							

National Semiconductor
2000 Semiconductor Dr., Santa Clara, CA 95052-8000

**CERPACK,
14 LEAD,
GULL WING**

Revision History

Rev	ECN #	Rel Date	Originator	Changes
0C1	M0003344	04/12/99	Rose Malone	Update MDS: MJLM148-X, Rev. 0B0 to MJLM148-X, Rev. 0C1. Added reference to JL148BZA to Main Table, Absolute Section and graphics.